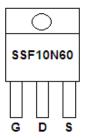


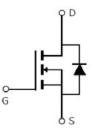
Main Product Characteristics:

V _{DSS}	600V
R _{DS} (on)	0.69Ω (typ.)
I _D	10A









220

Marking and pin Assignment

Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V①	10	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V①	6	А
I _{DM}	Pulsed Drain Current [®]	40	
	Power Dissipation3	156	W
P _D @TC = 25°C	Linear Derating Factor	1.25	W/°C
V _{DS}	Drain-Source Voltage	600	V
V _{GS}	Gate-to-Source Voltage	± 30	V
E _{AS}	Single Pulse Avalanche Energy @ L=14.2mH	641	mJ
I _{AS}	Avalanche Current @ L=14.2mH	9.5	А
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{eJC}	Junction-to-case③	—	0.8	°C/W
В	Junction-to-ambient (t \leq 10s) ④	—	62	°C/W
R _{θJA}	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source breakdown voltage	600	_	_	V	V _{GS} = 0V, ID = 250µA	
D			0.69	0.8	0	V_{GS} =10V,I _D = 5A	
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	1.60	—	Ω	T _J = 125℃	
Maarin	Gate threshold voltage	2	_	4	v	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
$V_{GS(th)}$	Gate meshold voltage	_	1.8	—	v	T _J = 125℃	
	Drain to Source lookage ourrent	—	—	1		$V_{DS} = 600V, V_{GS} = 0V$	
I _{DSS}	Drain-to-Source leakage current	—	—	50	μA	T _J = 125℃	
	Cata ta Causa famuand laakana		_	100	- 1	V _{GS} =30V	
I _{GSS} Gate-to-Source for	Gate-to-Source forward leakage		_	-100	nA	V _{GS} = -30V	
Q_{g}	Total gate charge	—	25.09	—		I _D = 9.5A,	
Q_{gs}	Gate-to-Source charge	—	7.74	—	nC	V _{DS} =480V,	
Q_{gd}	Gate-to-Drain("Miller") charge		8.87	_		$V_{GS} = 10V$	
t _{d(on)}	Turn-on delay time	—	20.2	—			
tr	Rise time	—	37.2	—		V_{GS} =10V, VDS=320V, R _L =33.8 Ω ,R _{GEN} =25 Ω ID=9.5A	
t _{d(off)}	Turn-Off delay time		65.2	_	ns		
t _f	Fall time	_	40.2	_			
C _{iss}	Input capacitance	—	1257			$V_{GS} = 0V$	
Coss	Output capacitance	—	159		pF	V _{DS} = 25V	
C _{rss}	Reverse transfer capacitance	_	1.36	—]	f = 1MHz	

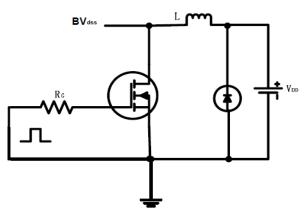
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			10	^	MOSFET symbol
IS	(Body Diode)		10	A	showing the _G	
I _{SM}	Pulsed Source Current	_	_	40	А	integral reverse
	(Body Diode)					p-n junction diode.
V _{SD}	Diode Forward Voltage	—	0.92	1.4	V	I _S =10A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	—	745	_	ns	$T_J = 25^{\circ}C, I_F = 9.5A,$
Q _{rr}	Reverse Recovery Charge	—	4841		nC	di/dt = 100A/µs

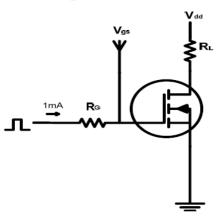


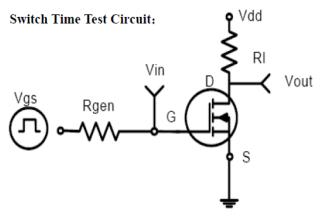
Test circuits and Waveforms

EAS test circuits:

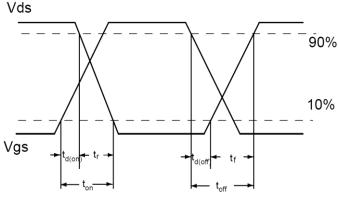


Gate charge test circuit:





Switch Waveforms:



Notes:

- ①The maximum current rating is limited by bond-wires.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- (5) These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =150°C.



Typical electrical and thermal characteristics

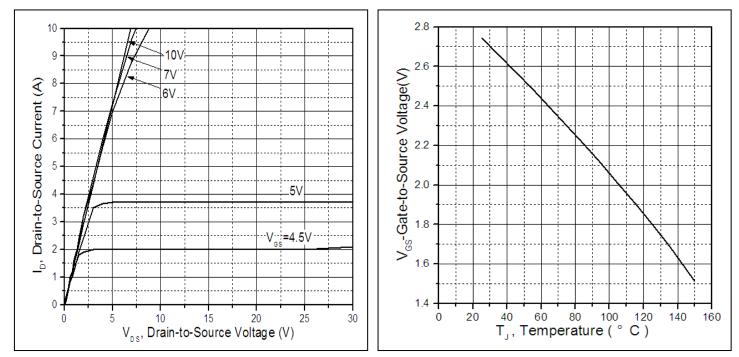


Figure 1: Typical Output Characteristics

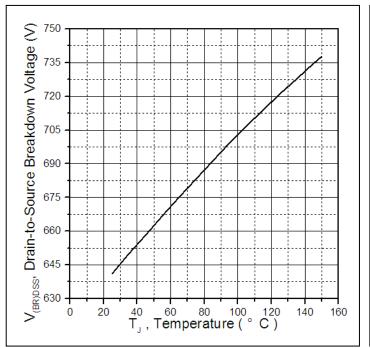


Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature

Figure 2. Gate to source cut-off voltage

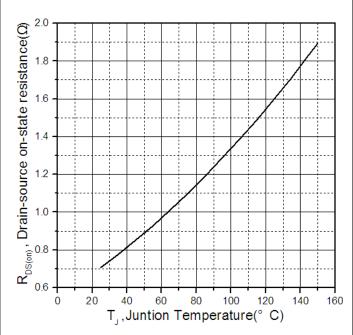


Figure 4: Normalized On-Resistance Vs. Case Temperature



С

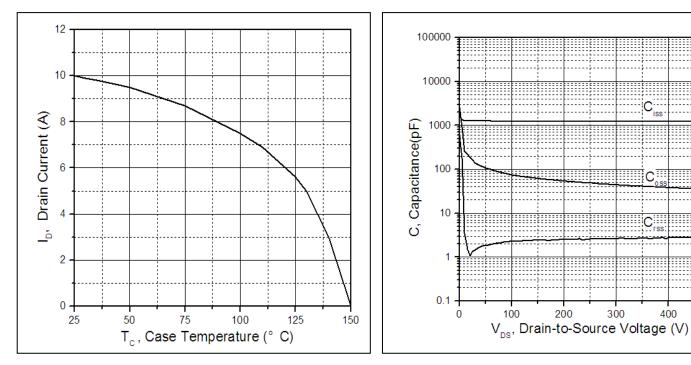
С

C

400

500

300



Typical electrical and thermal characteristics



Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

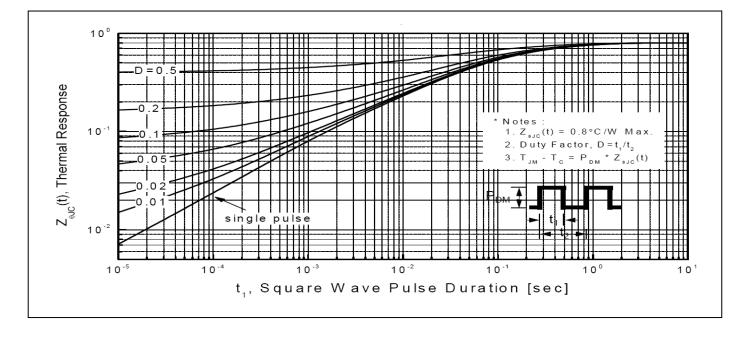
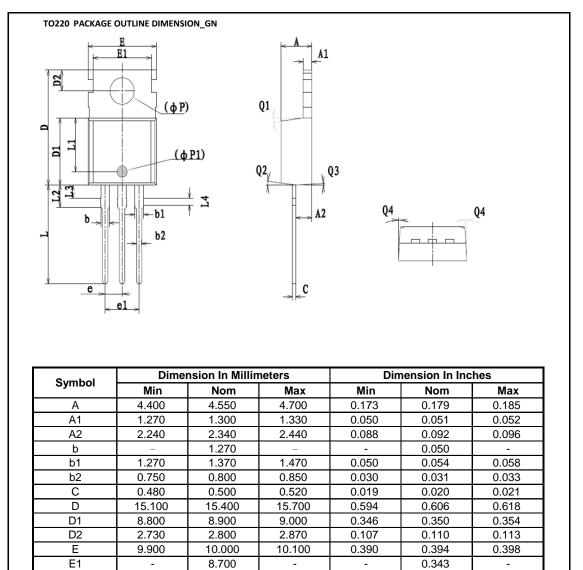


Figure7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



3.630

1.600

13.570

3.100

1.850

1.100

9⁰

9⁰

9⁰

5⁰

3.600

1.500

2.54BSC

5.08BSC

13.360

7.35REF

3.000

1.750

1.000

7⁰

7⁰

7⁰

3⁰

0.141

0.055

0.518

0.114

0.065

0.035

5⁰

5⁰

5⁰

1⁰

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ΦP

ΦΡ1

е

e1

L

L1 L2

L3

L4

Q1

Q2

Q3

Q4

3.570

1.400

13.150

2.900

1.650

0.900

5⁰

5⁰

5⁰

1⁰

0.142

0.059

0.1BSC

0.2BSC

0.526

0.29REF

0.118

0.069

0.039

7⁰

7⁰

7⁰

3⁰

0.143

0.063

0.534

0.122

0.073

0.043

9⁰

9⁰

9⁰

5⁰



Ordering and Marking Information

Device Marking: SSF10N60	
Package (Available)	
TO220	
Operating Temperature Range	
C : -55 to 150 ⁰C	

Devices per Unit

Package Type	Units/ Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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